

1449

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02578.0006.US00

SERIAL NO.

09/611,219

PATENTS AND OTHER ITEMS FOR APPLICANT'S
INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT:

Scott A. Chalmers, et al.

FILING DATE:

July 6, 2000

GROUP:

2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
JP	AA	5,436,725	07/25/95	Ledger	356	357	10/12/93

FOREIGN PATENT DOCUMENTS

FOREIGN PARENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO	
JP	AB	EP 0 644 399 A2	22.03.1995	Europe (Dainippon Screen Mfg. Co. Ltd.)				
JP	AC	EP 0 663 265 A1	19.07.1995	Europe (International Business Machines Corporation)				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

JP	AD	Jones, G.R. et al., <i>Chromatic Interferometry for an Intelligent Plasma Processing System</i> , MEASUREMENT SCIENCE & TECHNOLOGY , Vol. 5, No. 6, June 1994 (1994-06), Pages 639-647, XP 000456344; Bristol, GB.
JP	AE	Lange, V. et al., <i>Reflexionsinterferometrie zur Kontrolle dünner Silizium-Membranen</i> , TECHNISCHES MESSEN , Vol. 61, No. 9, September, 1994 (1994-09), pages 346-351, XP000465894, pages 346-351, figures 1-4
JP	AF	ImSpector Imaging Spectrograph brochure including specifications, Spectral Imaging Ltd. , Oulu, Finland, (3 pages)
JP	AG	CCD Detectors, Optical Systems Division , retrieved on-line 6/21/00, (3 pages)
JP	AH	<i>Advanced Thin Film Measurements – About thin Film</i> , Filmetrics , retrieved on-line 6/21/00; pages 1-6
JP	AI	<i>Advanced Thin Film Measurements – Operation</i> , Filmetrics , retrieved on-line 6/21/00; pages 1-2
JP	AJ	<i>Advanced Thin Film Measurements – PTFEON Data</i> , Filmetrics , retrieved on-line 6/21/00; (1 page)
JP	AK	<i>Advanced Thin Film Measurements – faq</i> , Filmetrics , retrieved on-line 6/21/00; (2 pages)

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
1/18	4,555,767	11/26/85	Case et al.			10/28/92
1/18	5,747,813	05/05/98	Norton et al.			04/14/94

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO
1/18	EP 0 652 415 A1	05/10/95	(European) DE FR GB, IT, NL			X

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